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Introducing a Novel Spectral Analysis System for Measuring High-Performance Thin-Film Optical Filters

The HELIX Spectral Analysis System was designed to address the limitations of most commercially available spectrophotometers when measuring high-performance thin-film optical filters. The system's capabilities are four-fold: it is able to track filter edges to OD7 (-70 dB), evaluate blocking to OD9 (-90 dB), resolve edges as steep as 0.4% relative to edge wavelength from 90% transmission to OD7, and resolve passbands that are as narrow as 0.1 nm at full width half maximum (FWHM).

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